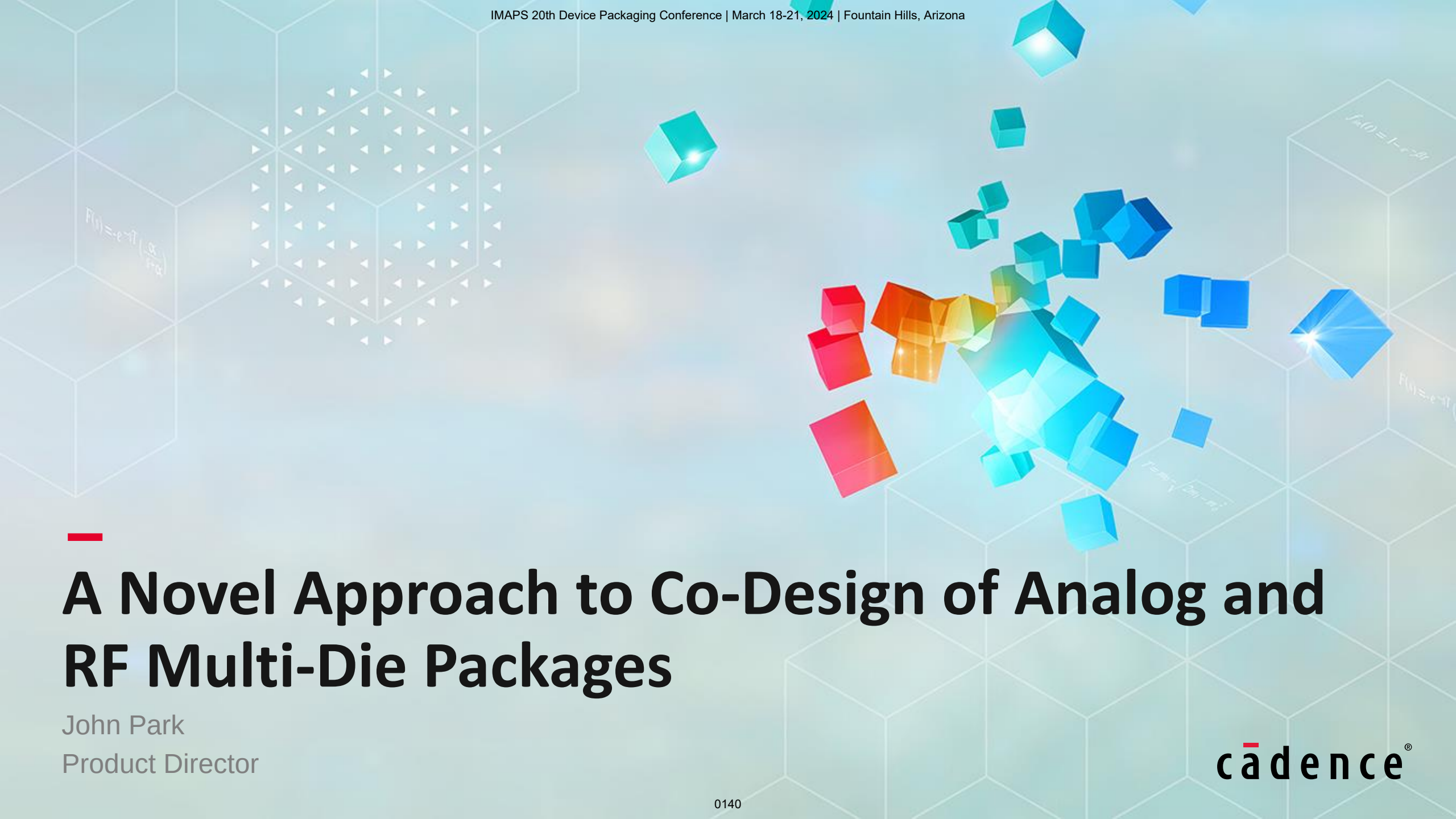




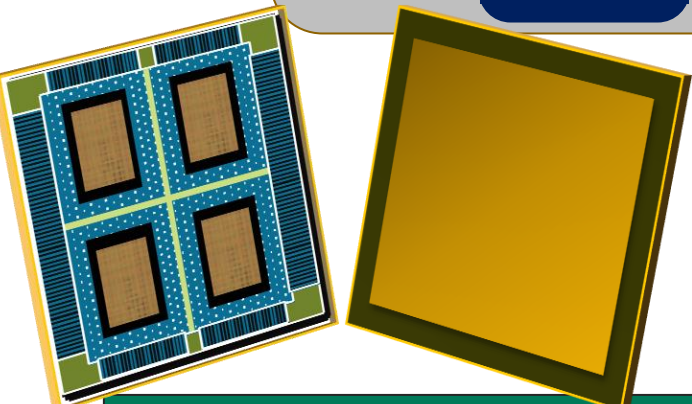
A Novel Approach to Co-Design of Analog and RF Multi-Die Packages

John Park
Product Director

 **cāden**ce®

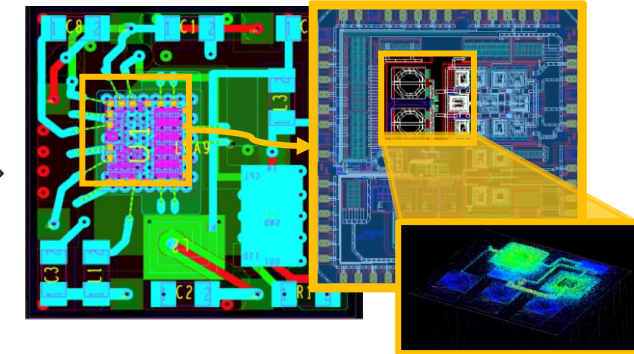
Analog/RF Market Landscape

The RF market is rapidly expanding with 5G, Automotive, and A&D



SiP module content and complexity, increasing with multiple technologies for IC, filters, switches, and other components

While SiP layout module content is increasing, geometries are getting smaller creating a higher risk for coupling



Disjointed tool flows are no longer sufficient to address the level of complexities and time-to-market constraints

The Needs of IC and Systems Designers are Converging

OSATs (SWaP)

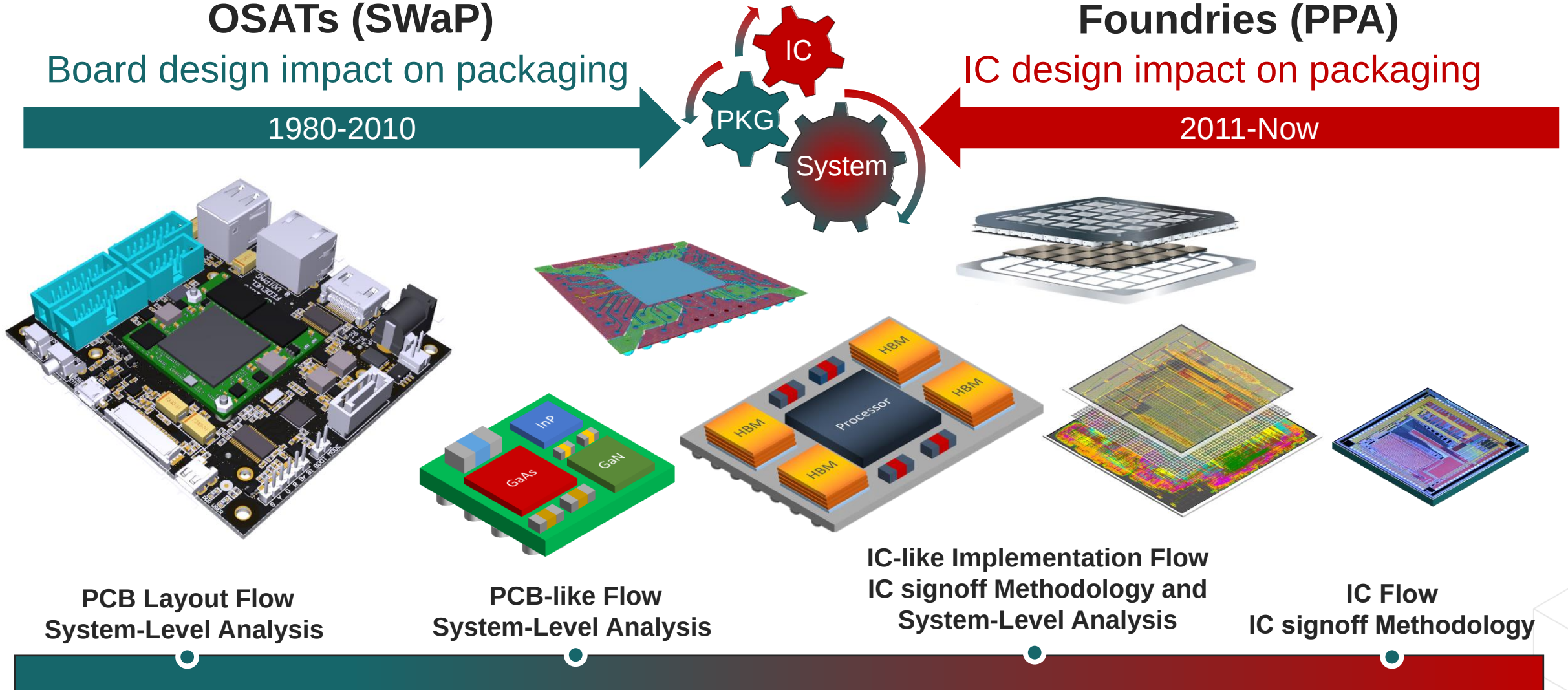
Board design impact on packaging

1980-2010

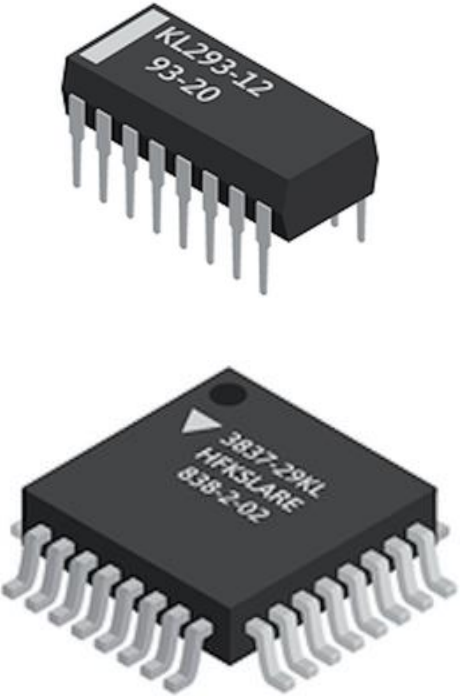
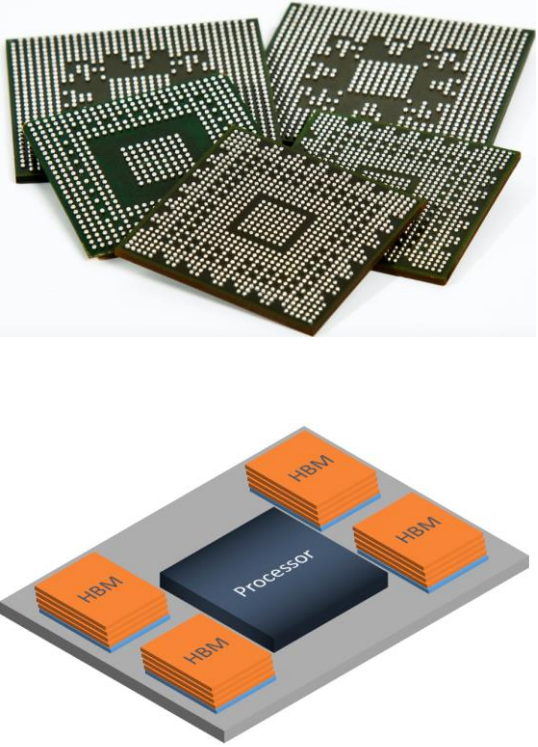
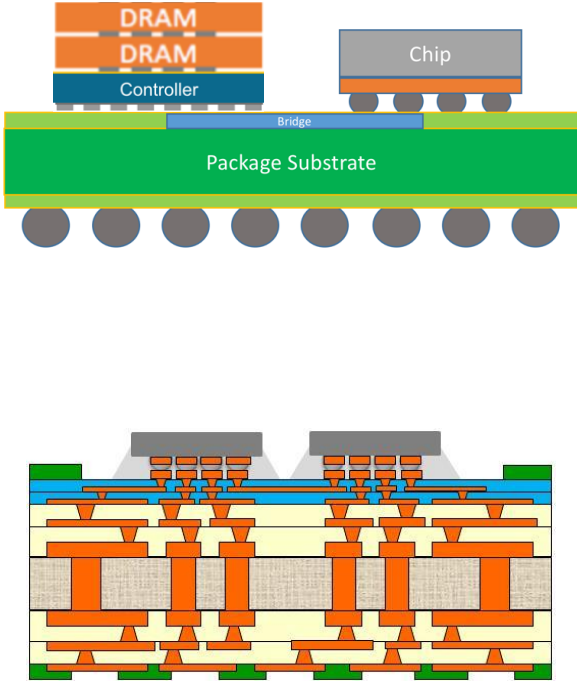
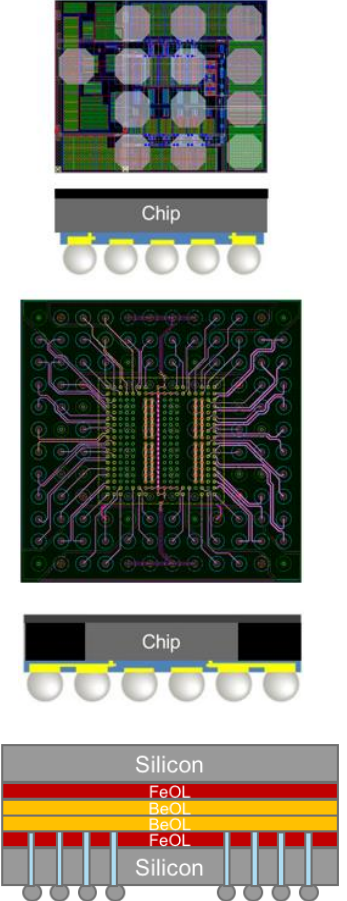
Foundries (PPA)

IC design impact on packaging

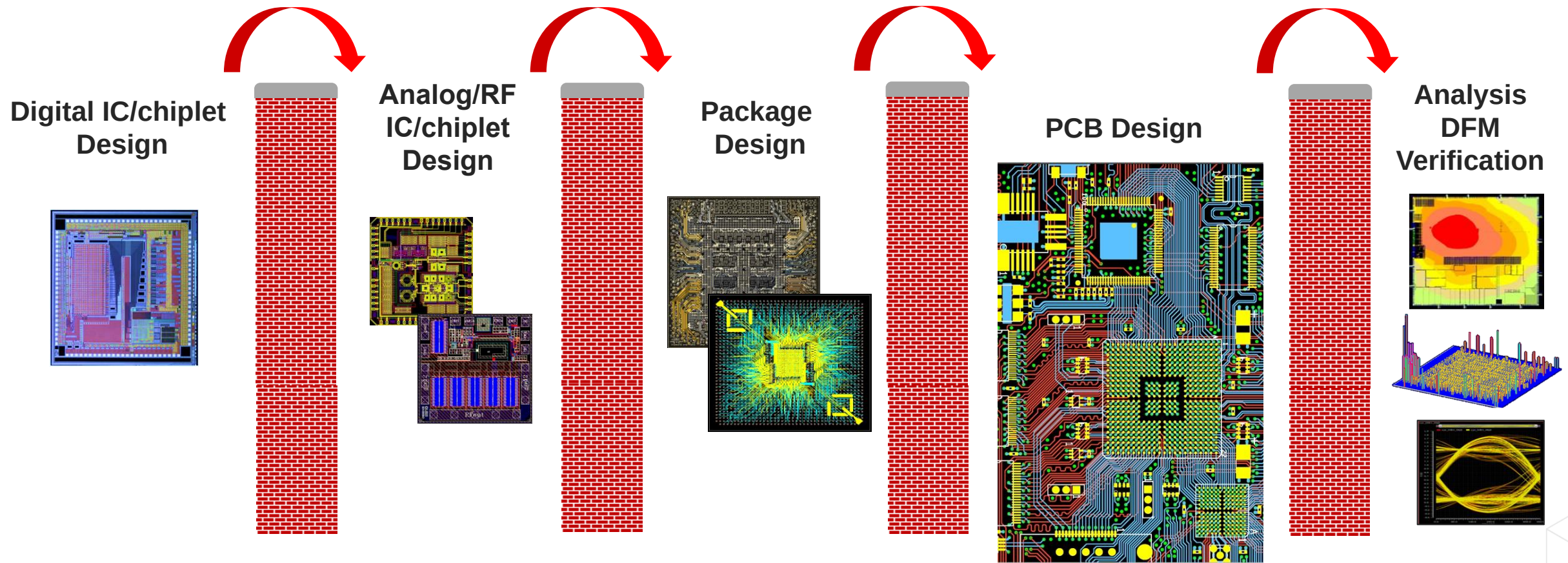
2011-Now



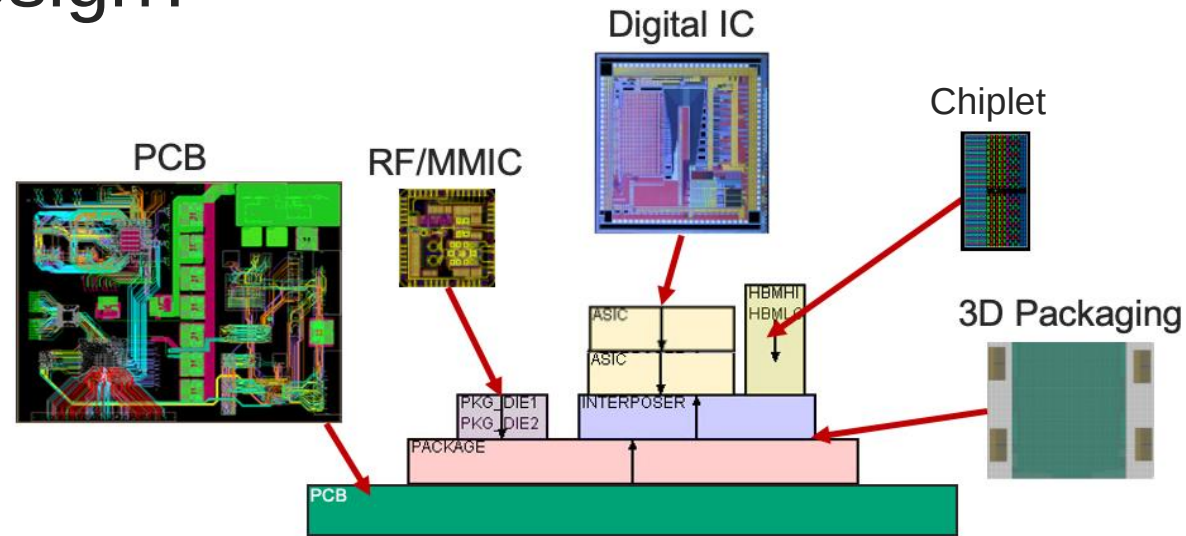
There is No One Way to Integrate/Package Die/Chipselets

Mechanical Leadframe	Substrate Based Organic, Ceramic, Silicon	Multi-Tech Substrates (Heterogeneous Substrates)	Substrate-less WLCSP, FOWLP & 3D IC
			

Over-the-Wall Design Approach Leads to Higher Costs, Longer Design Cycles and Lower Performance of Electronic Products



What is Co-Design?



Optimizing each device in context of the complete system

Digital ICs

Analog/RF ICs

Chiplets

Packaging

PCB

Partitioning/floor-planning in context of the complete system

I/O buffer placement and size

Power/Thermal (Heat)

D2D and full system level connectivity

Cross-device coupling/noise

Packaging technology tradeoffs

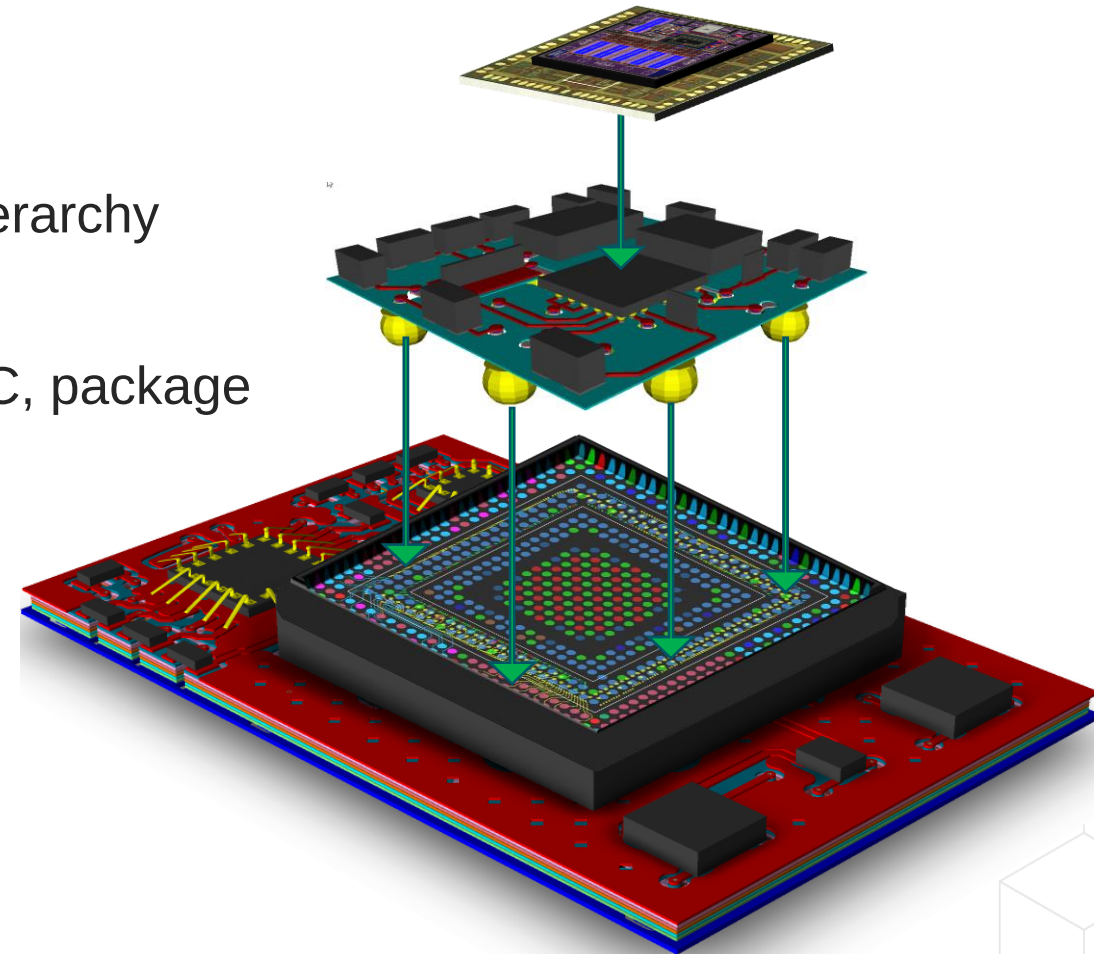
What's Needed From EDA to Enable Co-Design?

- Single design tool with concurrent editing
 - Is this possible? At what abstraction level?
- Common library across design tools
- Flexible connectivity use-model
 - Text, schematics and on-the-fly
- Seamlessly integrated system level analysis thought-out flow
 - Automatic parasitic stitching
- SystemLVS
- Assembly design kits (ADKs)
- Digital twinning
- AI/ML to improve automation



Co-Design Challenges of Analog/RF Multi-Die Systems

- Optimizing system-level performance
- Layout to EM loop
 - Design vs Layout is different in RF
 - Hard to hook up s-parameters into original design hierarchy
- Increase analysis fidelity and accuracy
 - Characterizing electromagnetic interactions across IC, package and even PCB
- SystemLVS is a big cause for re-spins
 - Common source for system-level connectivity (schematic)
 - Avoiding mistakes due to alignment of die(s), module, package and board
 - Implemented in different tools with different orientations and scaling

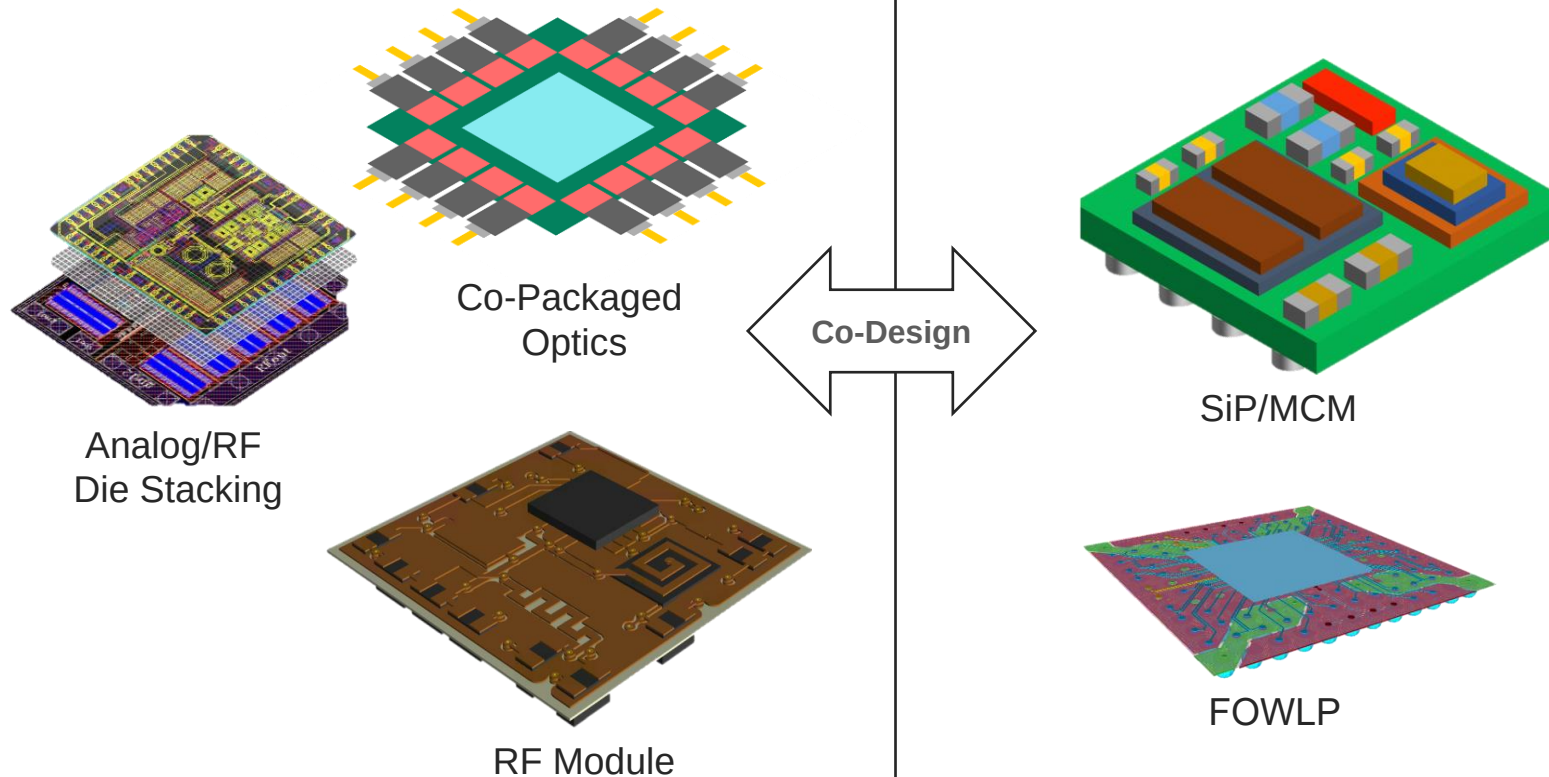


Analog/RF/Photonics Flow

Analog/RF IC Design Platform

Digital System Planner

Package Design



3D-EM, Electrical and Thermal Sign-Off

Single hierarchical schematic for complete system co-design

Multi-tech enables multi-PDK concurrent design

Edit-in-Concert advanced cross-domain co-design

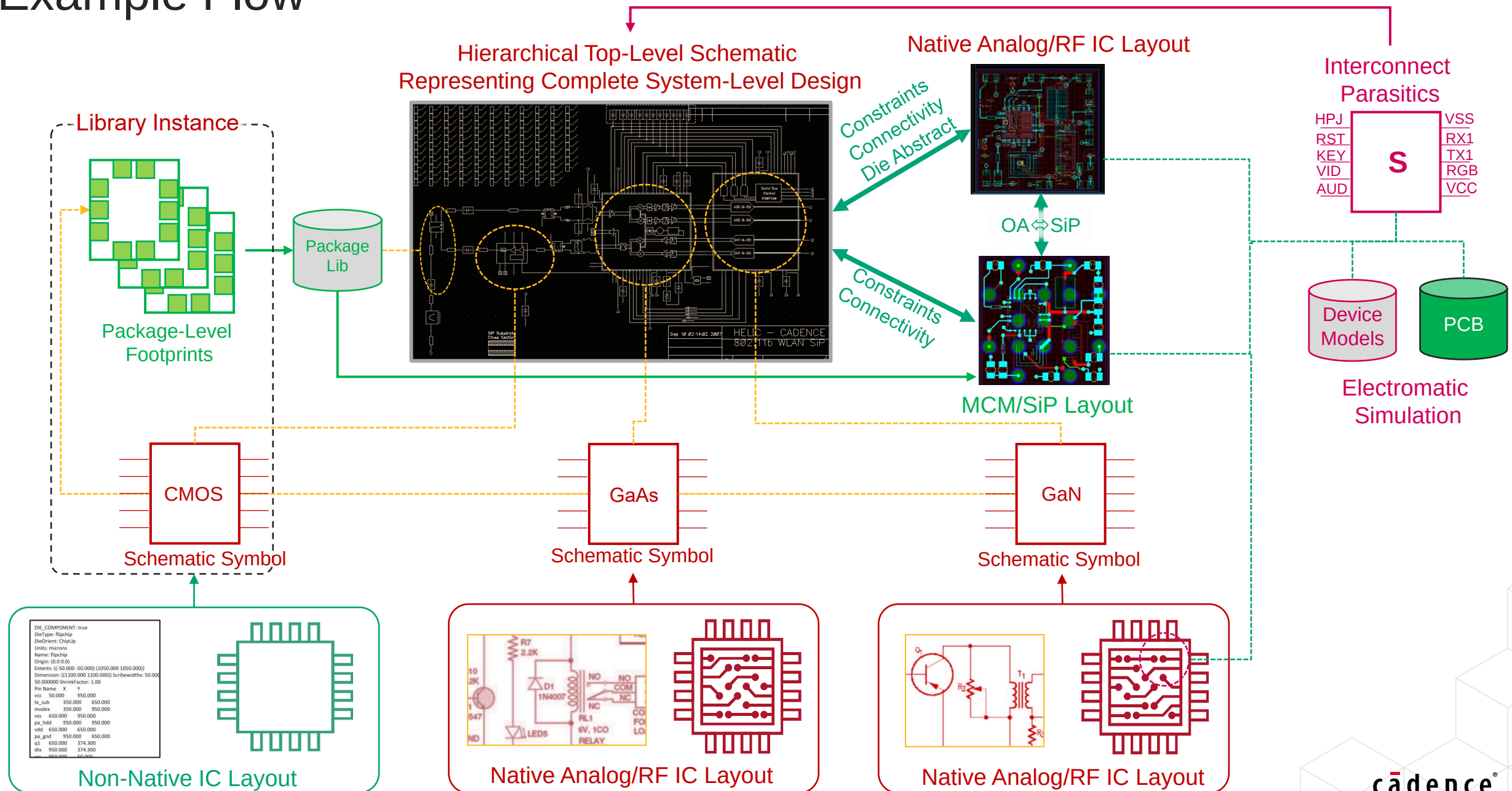
Seamless integration of on-chip and off-chip EM

Modeling of die to package cross-coupling effects

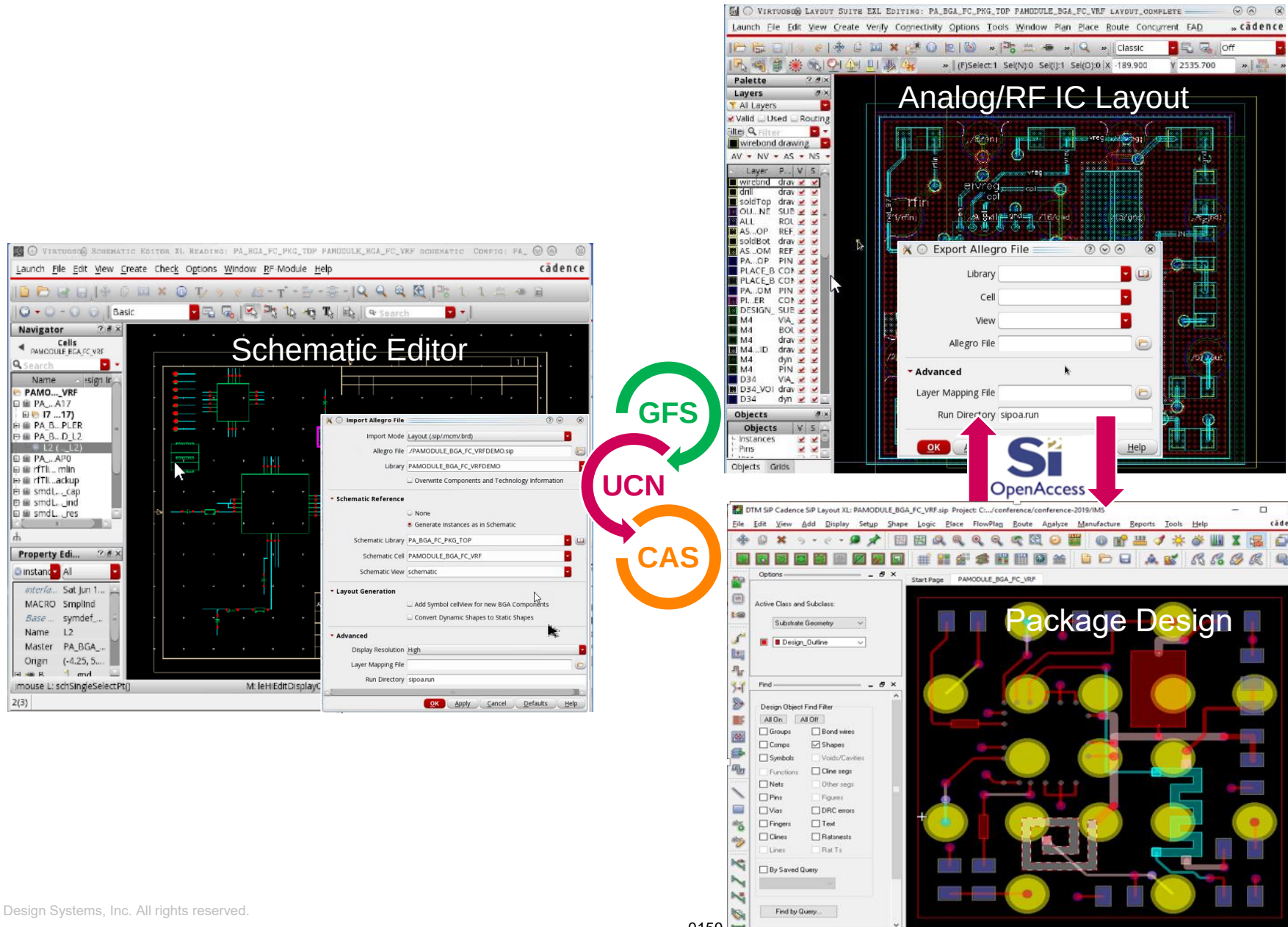
Automated layout parasitic back annotation flow

Unified library & SystemLVS

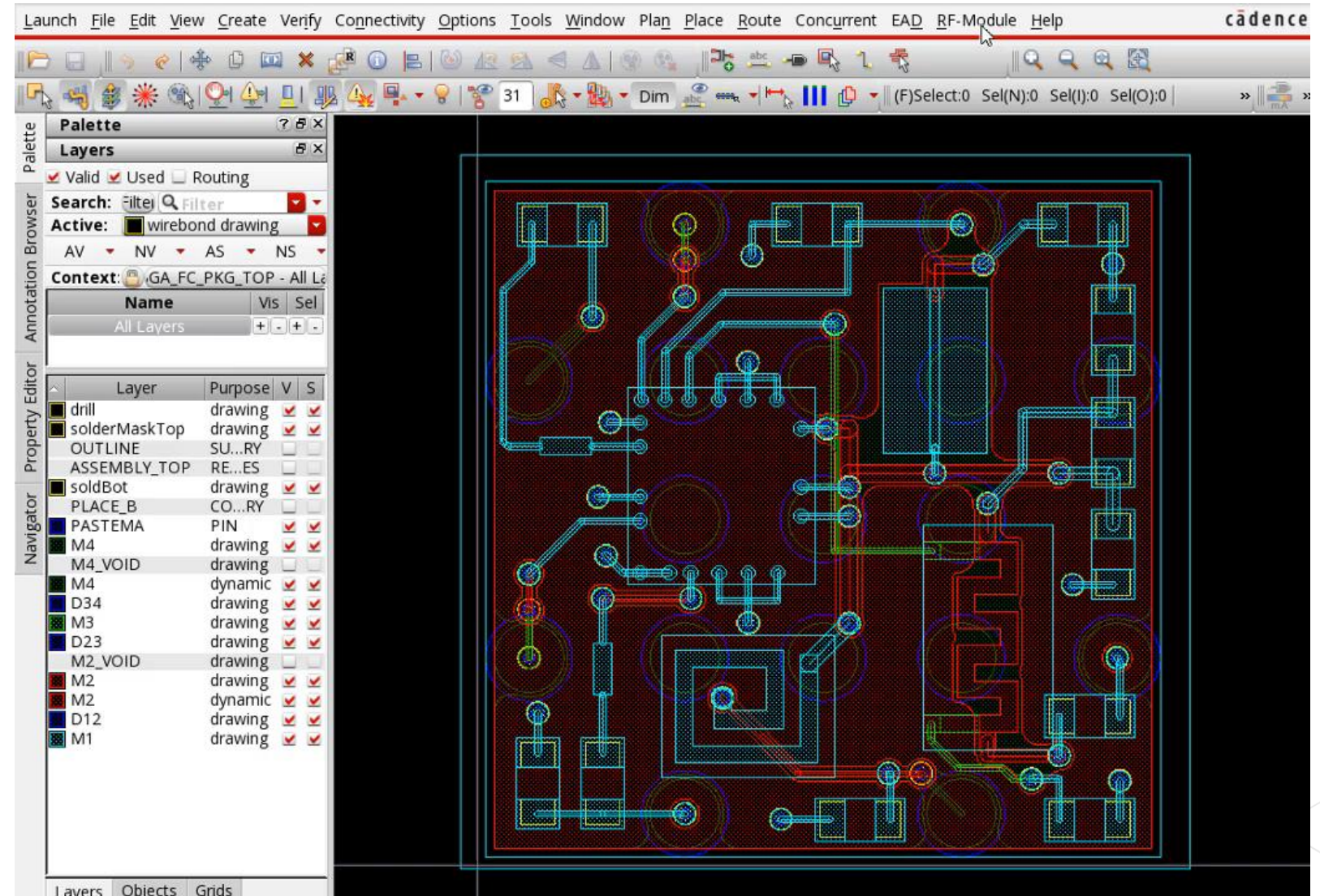
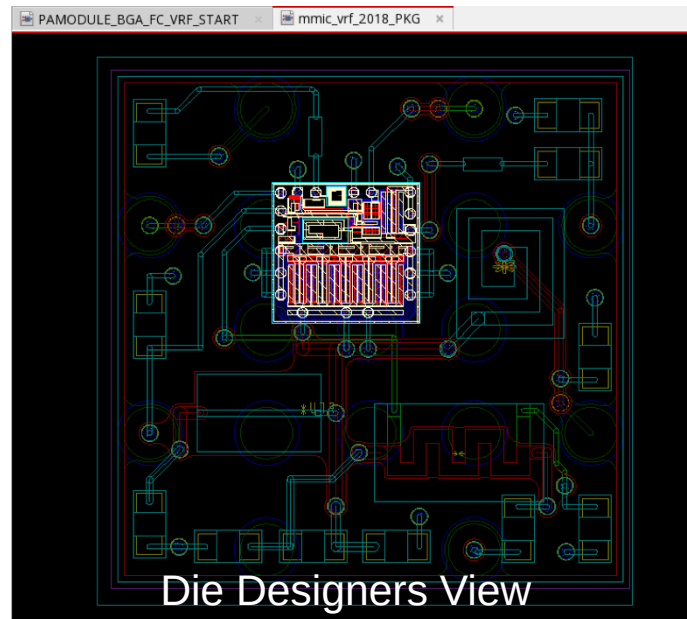
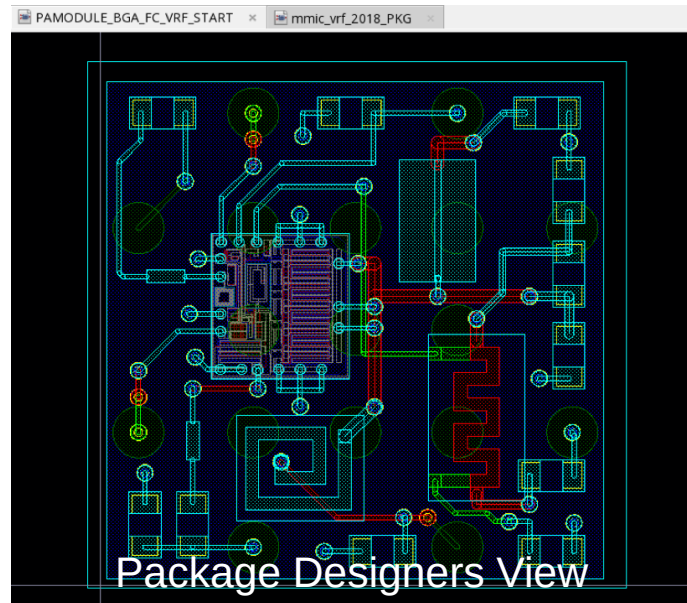
Example Flow



Single-Source System-Level Hierarchical Schematic

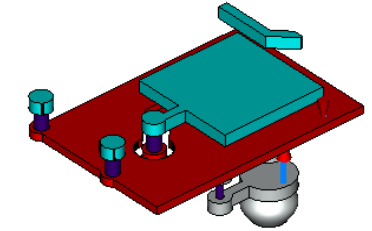


Common Database Enables True Physical IC/Package Co-Design



System-Level Layout Parasitic Back-Annotation and Simulation

- Coupled 3D-EM extraction between chip(let), package, and PCB layout databases
 - Electromagnetic extraction integrated through an assistant
 - Support for partial/full nets, groupings, and device-level modeling
 - Direct pin mapping and eliminates double-counting of discrete devices
 - S-parameters (freq. domain) and RLGC (time domain) models
- Automatically create schematics (extracted views) that include the layout parasitics from package and PCB
 - Must support multi-PDK, multi-die solutions (namespace collision avoidance)



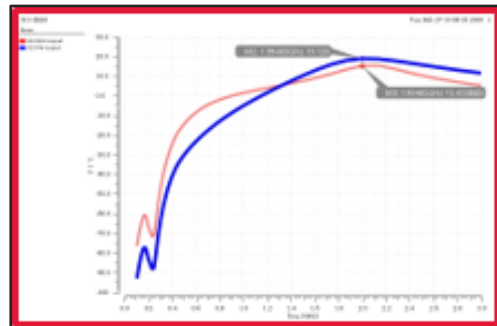
PowerSI Version: 16.0.0.02891.0 600
Computer Host Name: lnx-cm011

TouchstoneFormatFlag = 1
GNDNET GND

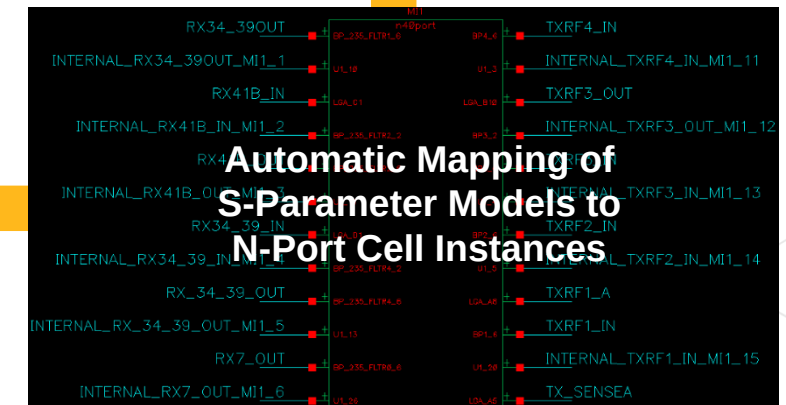
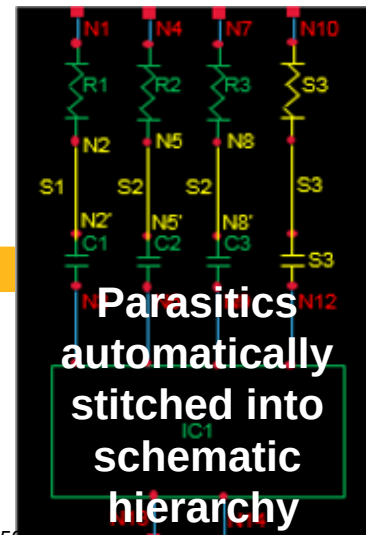
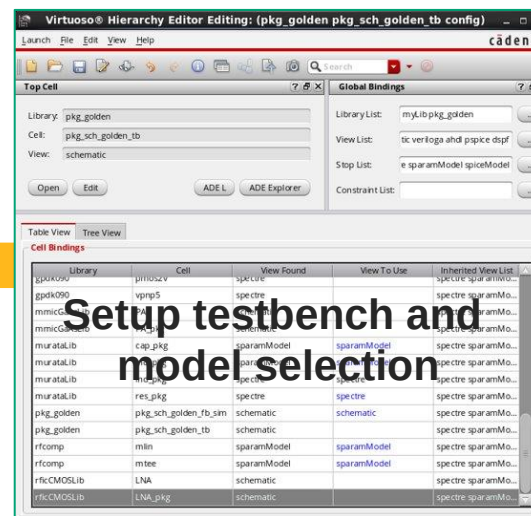
NETS: RX34_39OUT, RX34_39_IN, RX40A, RX40_3B, RX41A, RX41A_OUT, RX41B_IN, RX41B_OUT, RX7_OUT, TXRF2_IN, TXRF2_OUT, TXRF3_IN, TXRF3_OUT, TXRF4_IN, TXRF4_OUT, TXRF5_IN, TXRF5_OUT

Port 1 = BP_235_FILT1-6 RX34_39OUT
Port 2 = U1-18 RX34_39OUT
Port 3 = LGA-01 RX41B_IN
Port 4 = BP_235_FILT2-2 RX41B_IN
Port 5 = BP_235_FILT2-6 RX41B_OUT
Port 6 = U1-11 RX41B_OUT
Port 7 = LGA-01 RX34_39_IN
Port 8 = BP_235_FILT4-2 RX34_39_IN
Port 9 = BP_235_FILT4-6 RX34_39_OUT
Port 10 = U1-13 RX34_39_OUT
Port 11 = BP_235_FILT3-6 RX41B_OUT
Port 12 = U1-26 RX7_OUT
Port 13 = LGA-04 RX40A
Port 14 = U1-12 RX40A
Port 15 = LGA-07 RX40_3B
Port 16 = U1-17 RX40_3B
Port 17 = BP3-6 TXRF5_IN
Port 18 = U1-18 TXRF5_IN
Port 19 = LGA-010 TXRF4_OUT
Port 20 = BP4-2 TXRF4_OUT
Port 21 = BP4-6 TXRF4_IN
Port 22 = U1-3 TXRF4_IN
Port 23 = LGA-010 TXRF3_OUT
Port 24 = BP3-2 TXRF3_OUT
Port 25 = BP3-6 TXRF3_IN
Port 26 = U1-4 TXRF3_IN

S-Parameter Model

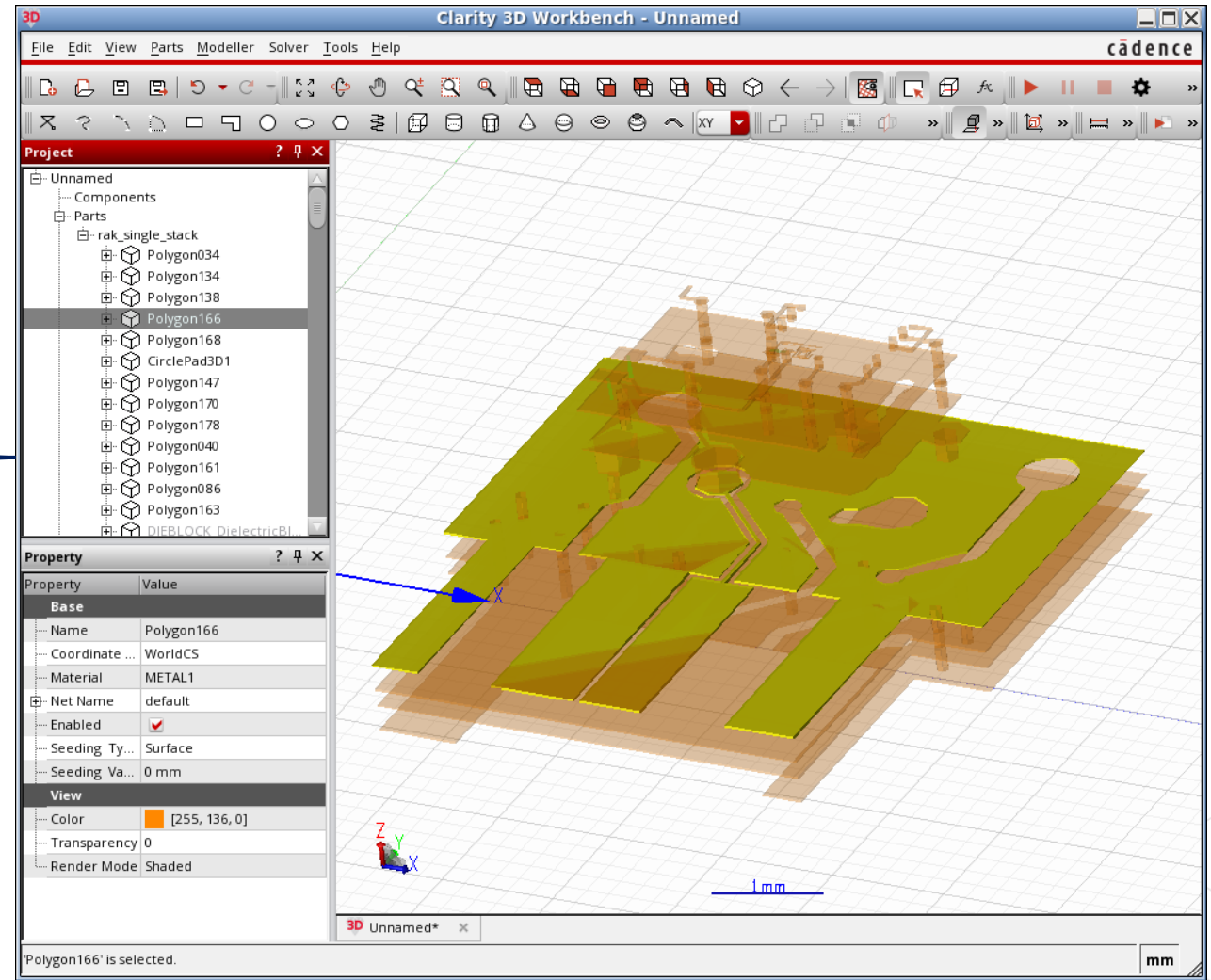
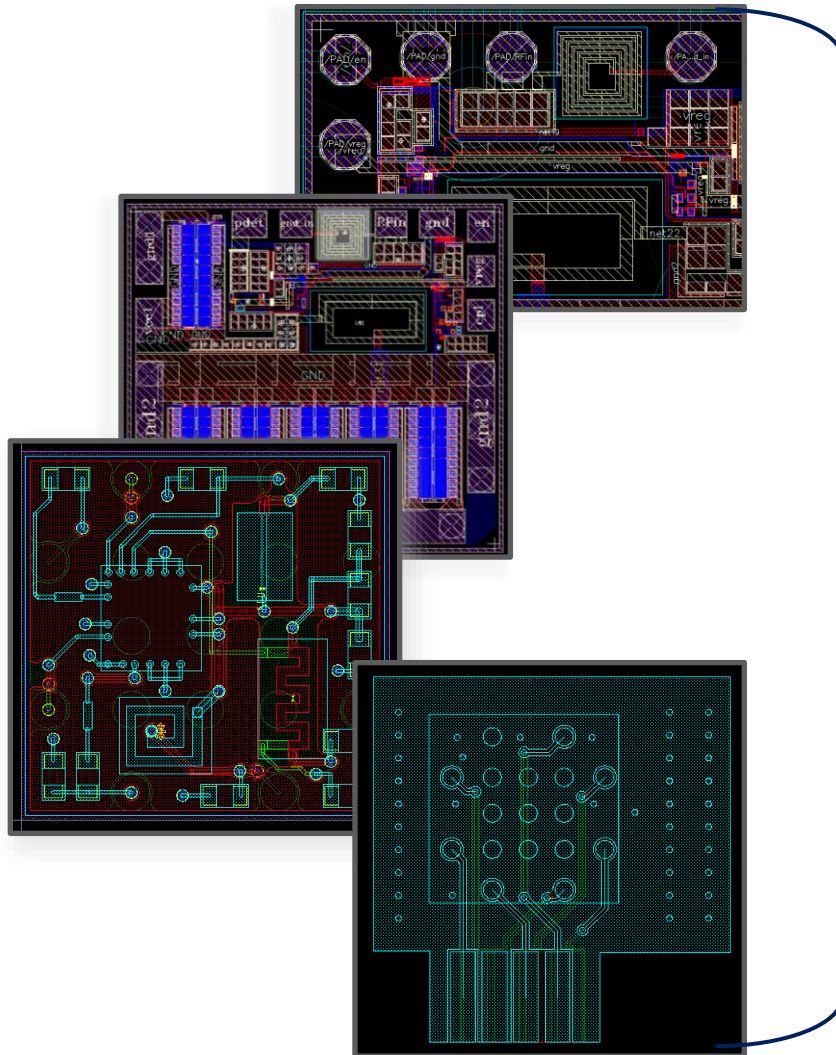


Simulate



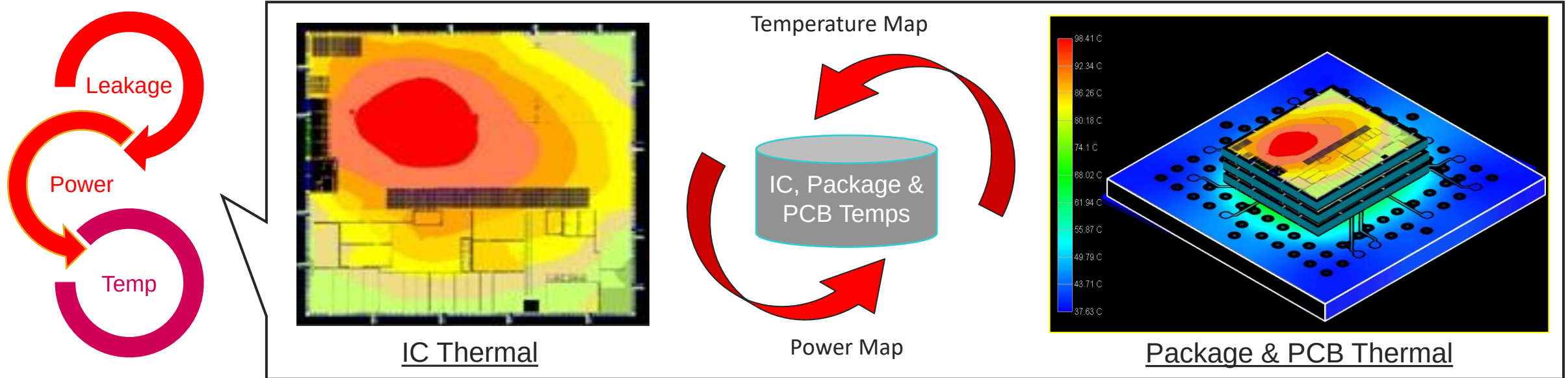
Circuit to System – Design and Analysis Solutions

System-level EM modeling



Electrical/Thermal Co-Analysis

Power/Thermal Co-Simulation

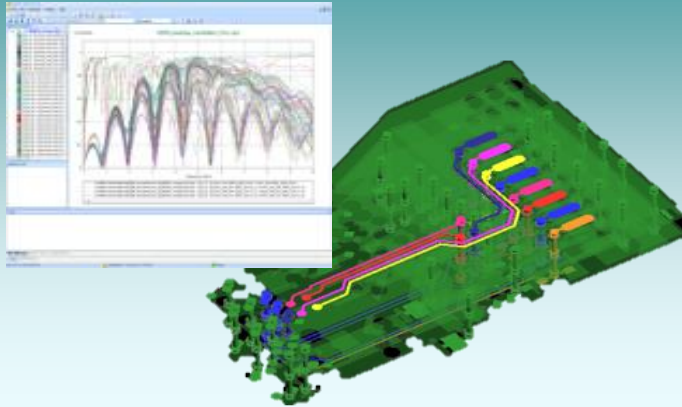


- Thermal runaway
 - Positive feedback and interaction among chip's temperature, leakage and power dissipation
 - Temperature-dependent EMIR failures
- Physics-based 3D thermal simulation
 - Solution generates temperature and location dependent "power-map" file
 - Technology to compute detailed temperature distribution for chip, package and PCB. Provides "temperature-map" file to die-level EMIR solution for iteration and convergence

Robust Technologies for System Analysis and Electrical Signoff

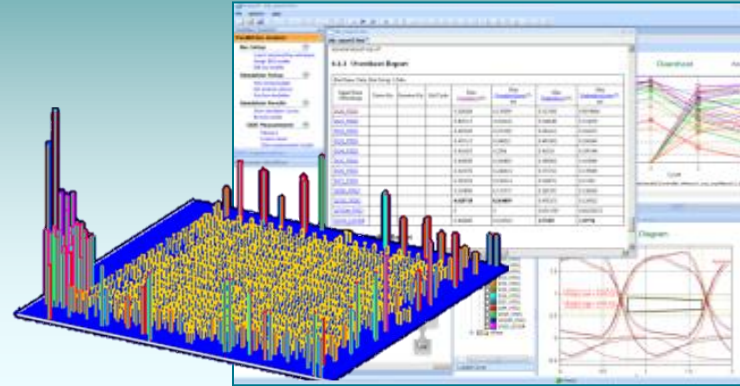
Electromagnetic (EM) Extraction

Massively parallelized matrix solver to model system-level interconnect with high accuracy



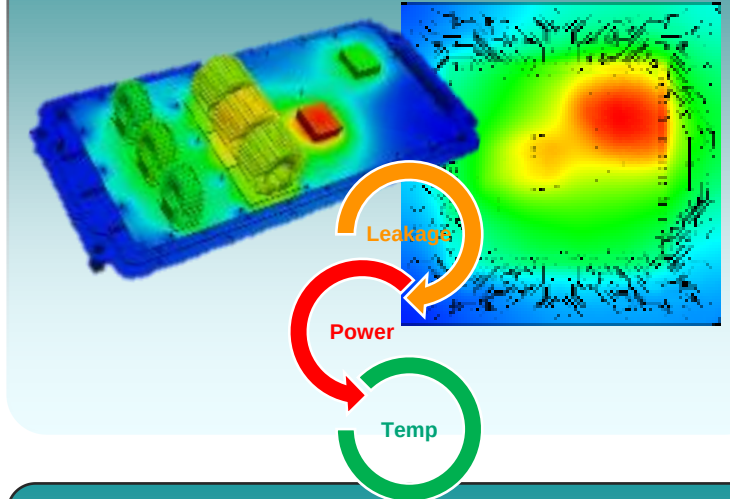
Signal and Power Integrity

Compliance Kits validate chiplet-to-chiplet connectivity
Coupled power and signal integrity analysis
Hybrid solver to model PCB and FC-BGA interconnect
XtractIM for full package model extraction



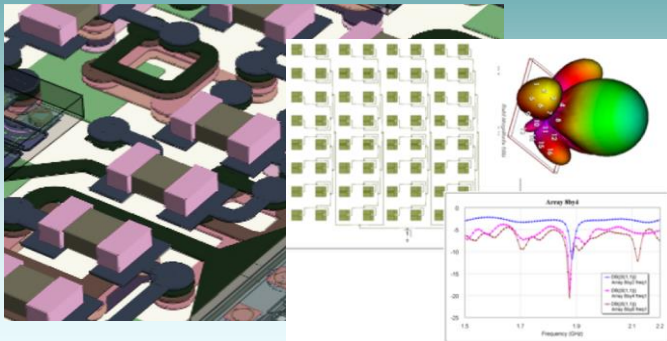
Electrical-Thermal Analysis

Steady-state and transient electro-thermal analysis with optional CFD engine



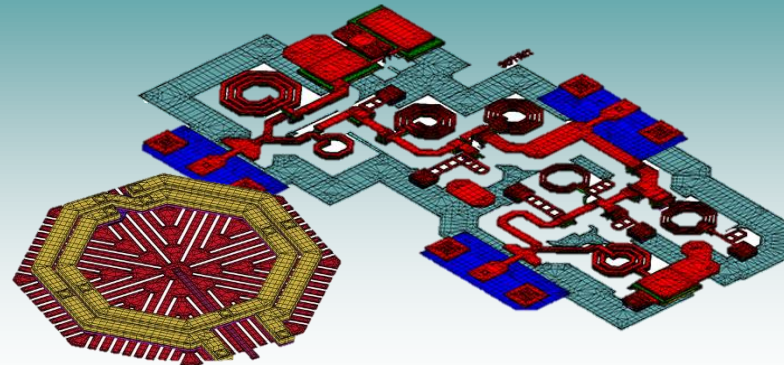
III/V Compound IC Modeling

Extraction of on/off-chip passive structures, transmission lines, planar antennas, and large patch arrays. Supports III/V devices.



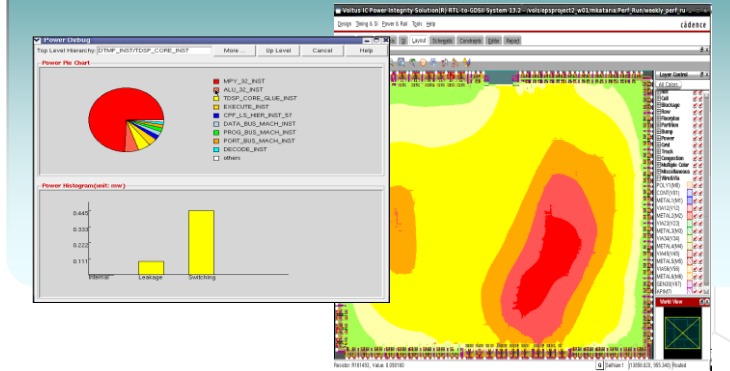
CMOS 3D EM

EM extraction for high-frequency, RF and AMS IC's



On-Die EMIR & Power Calculation

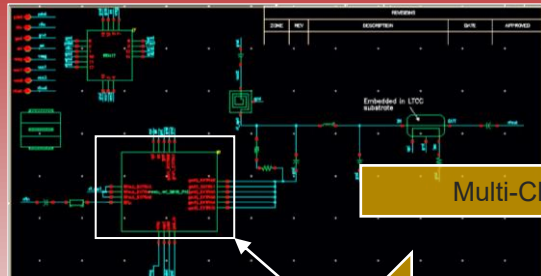
Leakage, internal and switching power
Vector-based or vector-less static and dynamic EMIR



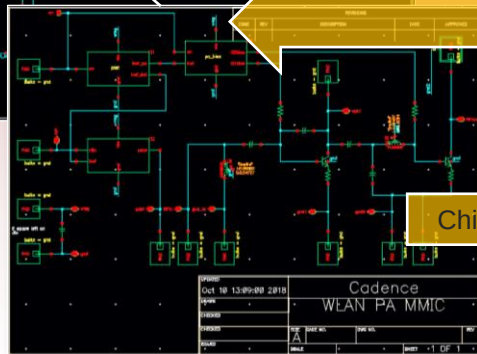
Integrated IC / Package / PCB / System Co-Design & Co-Analysis

Schematic-Driven Multi-PDK Design

Single system-level hierarchal schematic to drive multi-chip(let) design and verification



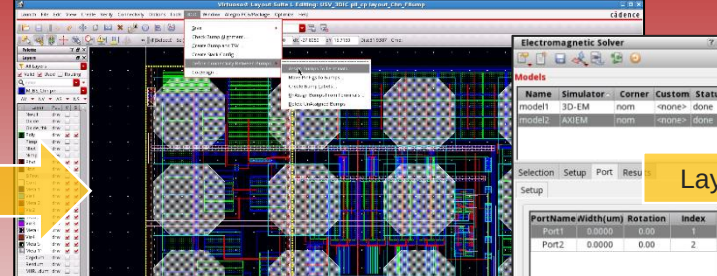
Multi-Chip(let) Layout



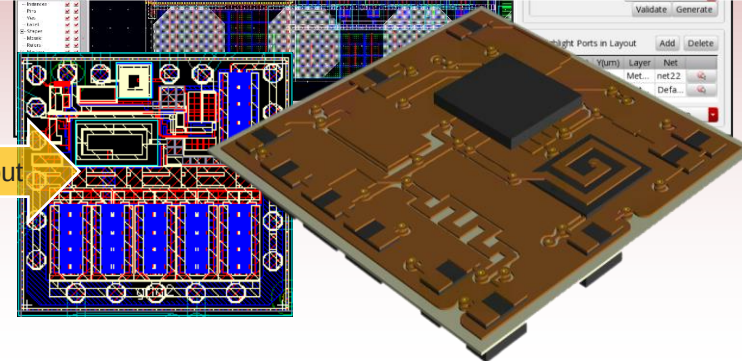
Chip(let) Layout

Cross-Platform Layout*

Seamless Virtuoso/Allegro cross-platform **co-design** of chips, chiplets, packages, and modules



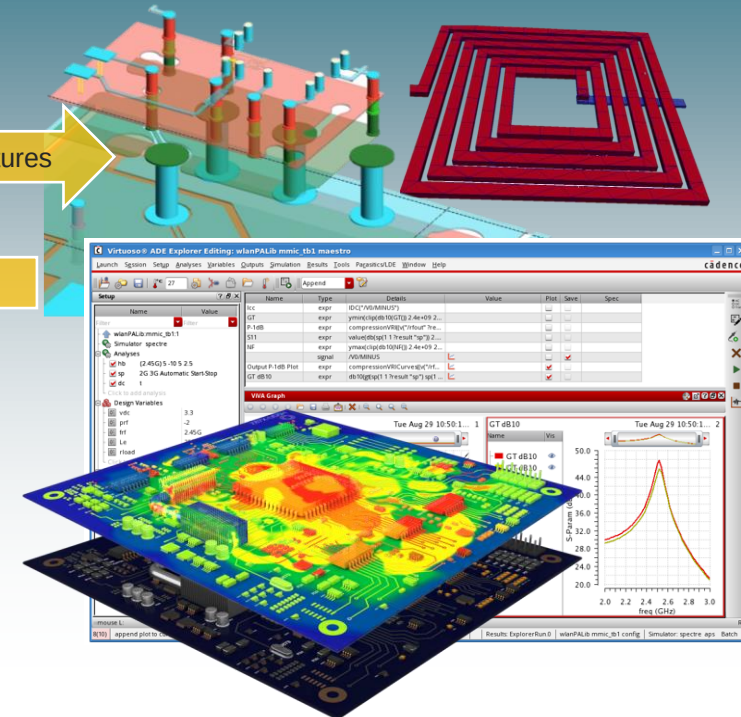
Seamless Layout/Device Parasitic Model Stitching

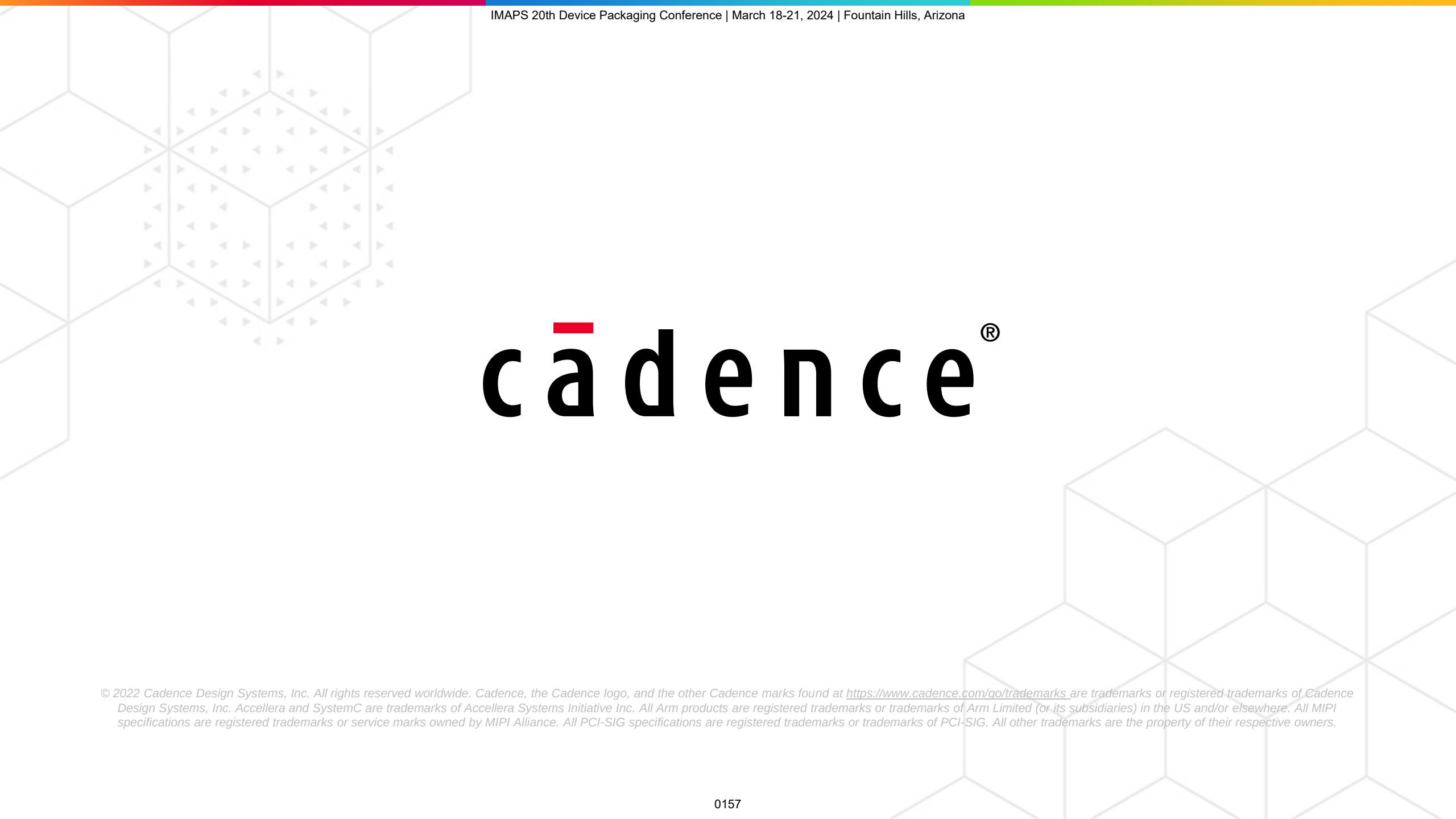


Layout Structures

On-Chip/Off-Chip EM/Thermal Modeling

Seamless integration with multiple EM extraction engines with automated schematic stitching and simulation flow





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